CEPC AHCAL Progress

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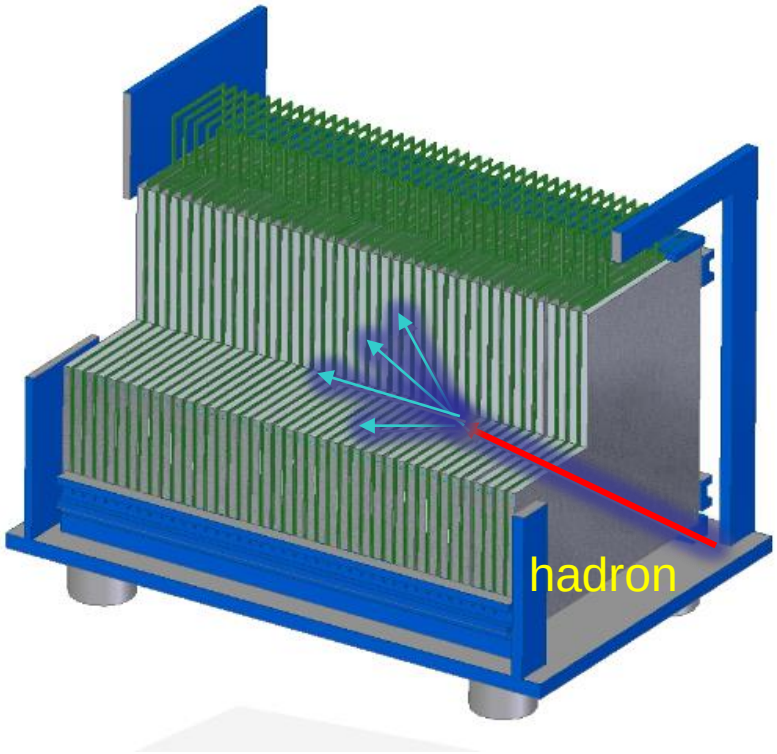
On behalf of CEPC Calorimeter working group

Outline

- Brief review of AHCAL of CEPC
- CEPC AHCAL Status
  - Scintillators mass production and test
  - SiPM batch test
  - HBU design
  - Cooling simulation
  - Mechanical Design
- Summary and outlook

AHCAL Prototype

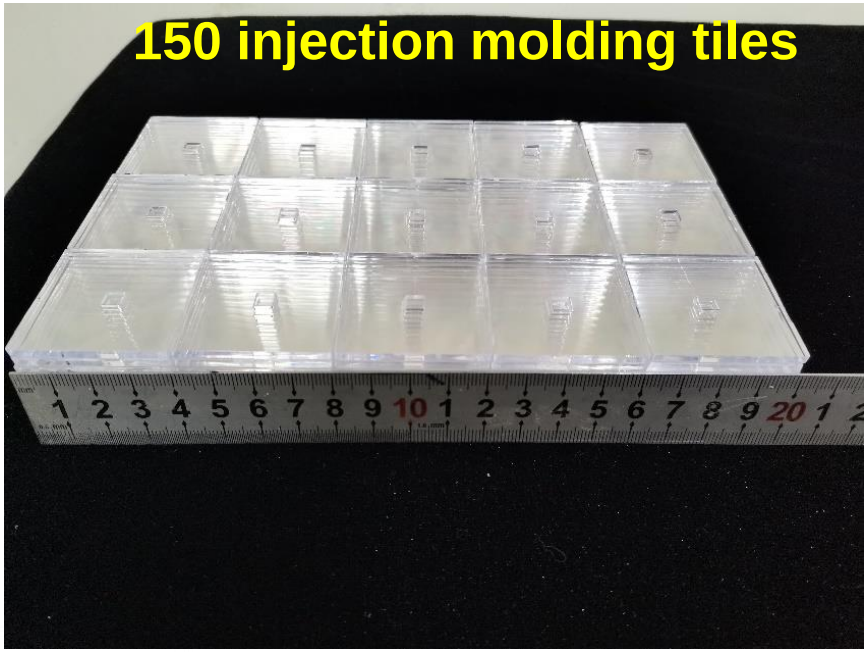
- Sampling Calorimeter
  - 40 layers, ~ 5 N.I.L
  - 72 cm×72 cm
- Absorber
  - Iron，2 cm thickness
- Sensitive Detector
  - Scintillator+SiPM，Number:13,960
  - Cell size：40 mm×40 mm×3mm
  - SiPM：HPK and NDL
- Electronics
  - SPIROC2E ASIC Chip

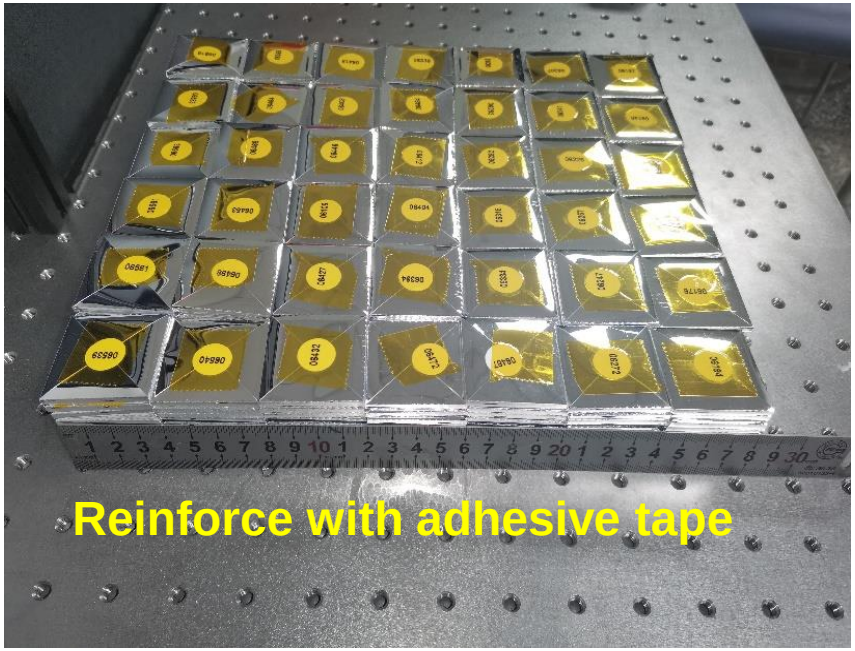


AHCAL Structure

Scintillator mass production and packaging

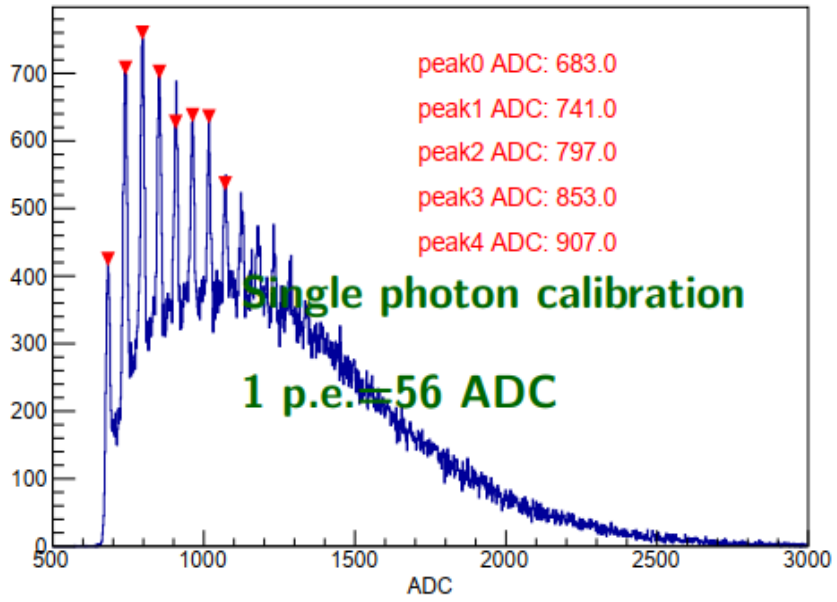
- More than 15000 scintillators were produced based on ejection molding and packaging using ESR film in August





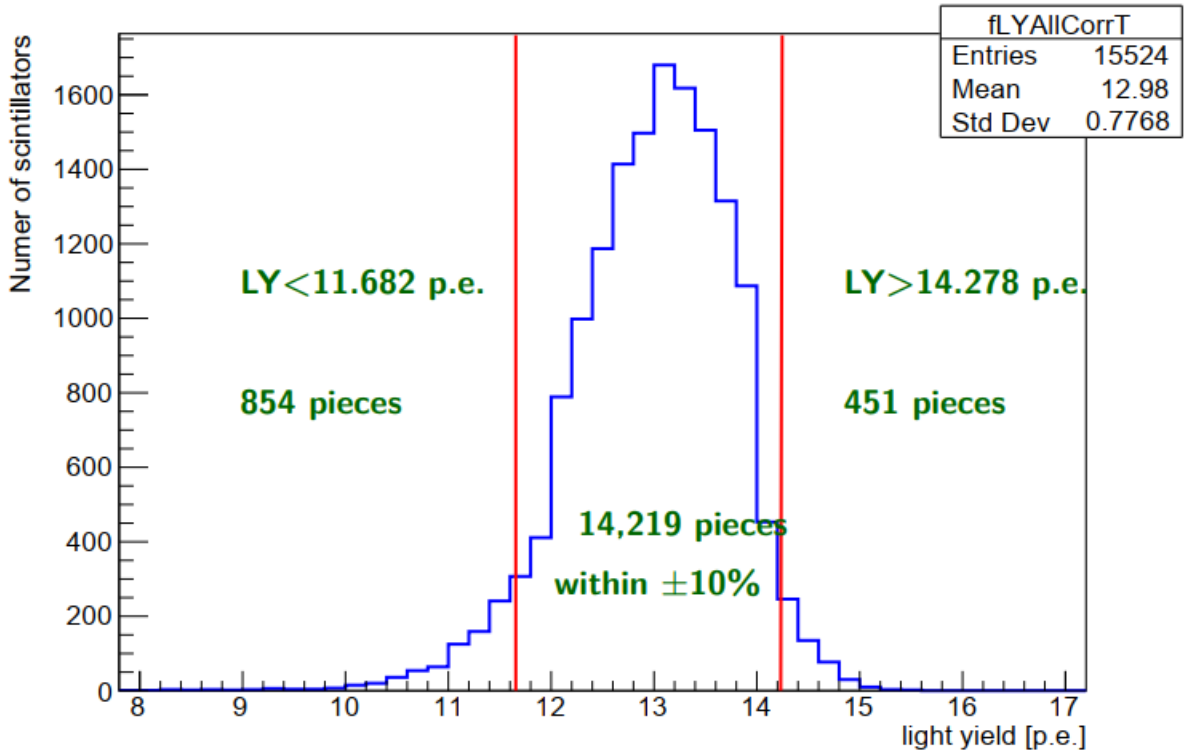
Scintillator batch test

- All the packaged scintillators (~15000) have been tested using Sr-90 β-ray source
  - SJTU, USTC
- The automatic displacement platform controls the movement of radioactive source and tests the scintillator one by one



Scintillator batch test

- 14,219 pieces within 10% of 15,524 pieces in total. About 91.6% of scintillators are qualified (within 10% of LY window).

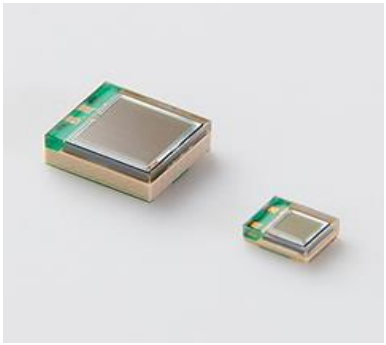


SiPM Procurement and testing

- Two different types SiPM were selected in this prototype
  - NDL, 1700 pieces
  - HAMAMATSU, ~13000 pieces

Company	NDL	HPK
Type	22-15	S14160-1315PS
Sensitive area (mm^2)	1.6*4	1.69
PDE (%)	40	32
Gain (*10^5)	2.4	3.6
Pixel No.	7400*4	7284
Breakdown Voltage (V)	28	38
OverVoltage (V)	4	4
Dark Count (kHz)	330*4	120
Cross Talk (%)	8.5	1.0

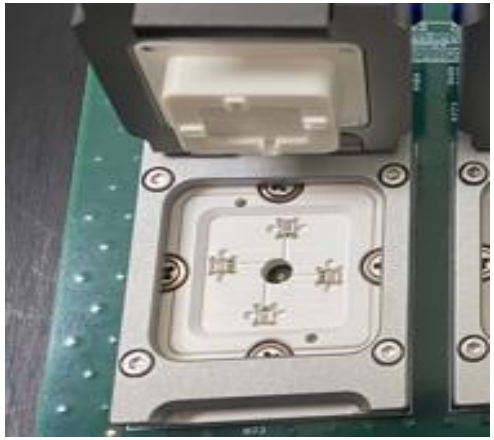
NDL



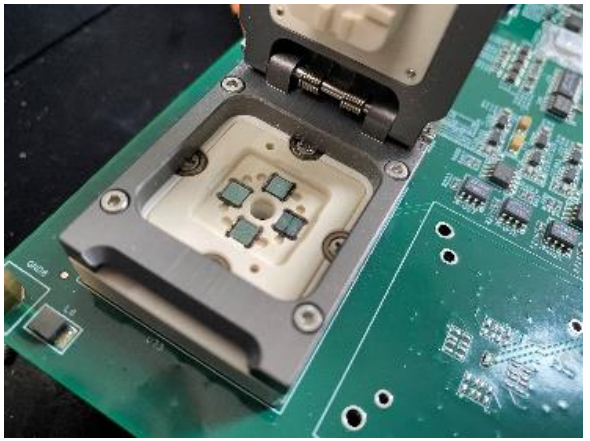
S14160-1315PS

SiPM bench test system

- Two sets of SiPM batch test systems were developed
  - NDL SiPM
  - HPK SiPM

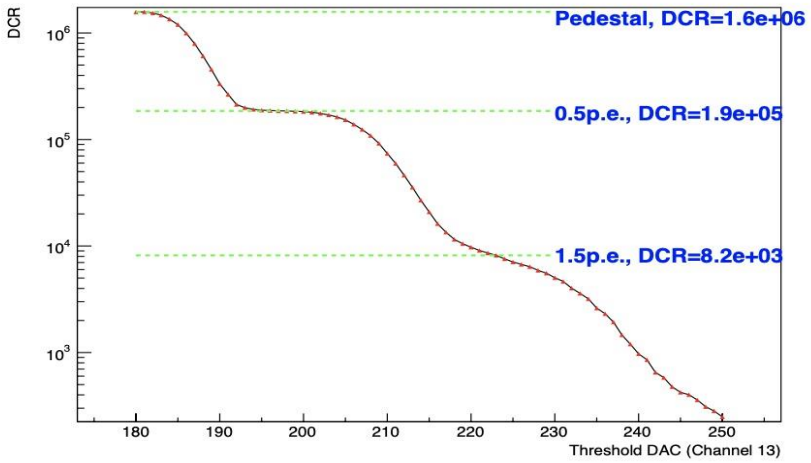


HPK

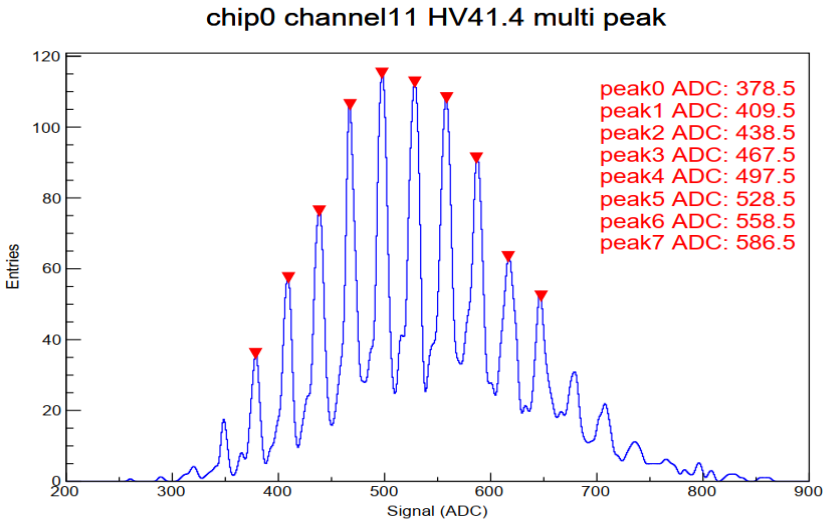


NDL

HPK SiPM Test



Dark Counting Rate



Photon-electron peak

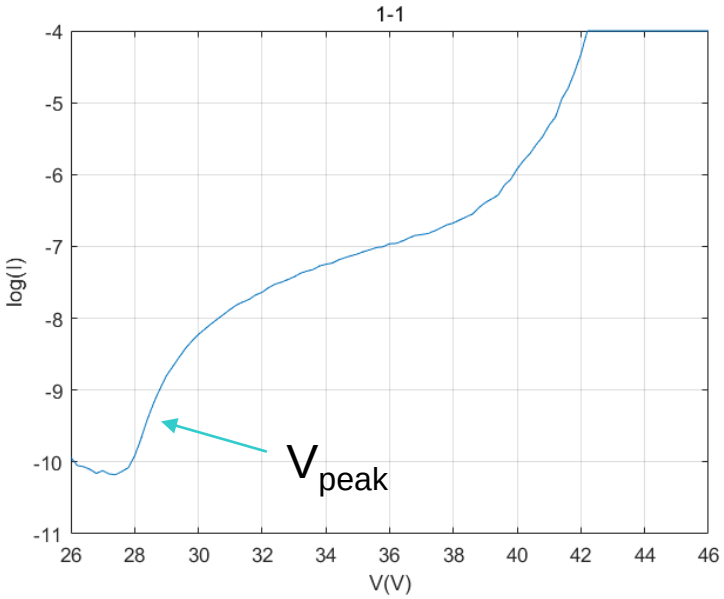
Electrical and optical characteristics (Typ. Ta=25 °C, VR=Vop, unless otherwise noted)

Parameter		Symbol	S14160				Unit
			-1310PS	-3010PS	-1315PS	-3015PS	
Spectral response range		λ	290 to 900				nm
Peak sensitivity wavelength		λp	460				nm
Photon detection efficiency at λp*3		PDE	18		32		%
Breakdown voltage*4		VBR	38±3				V
Recommended operating voltage*4		Vop	VBR + 5		VBR + 4		V
Vop variation within a reel		-	±0.1				V
Dark count rate*5	typ.	DCR	120	700	120	700	kcps
	max.		360	2100	360	2100	
Direct crosstalk probability		Pct	< 1				%
Terminal capacitance at Vop		Ct	100	530	100	530	pF
Gain		M	1.8×10^5		3.6×10^5		-
Temperature coefficient of Vop		ΔTVop	34				mV/°C

*3: Photon detection efficiency does not include crosstalk and afterpulses.

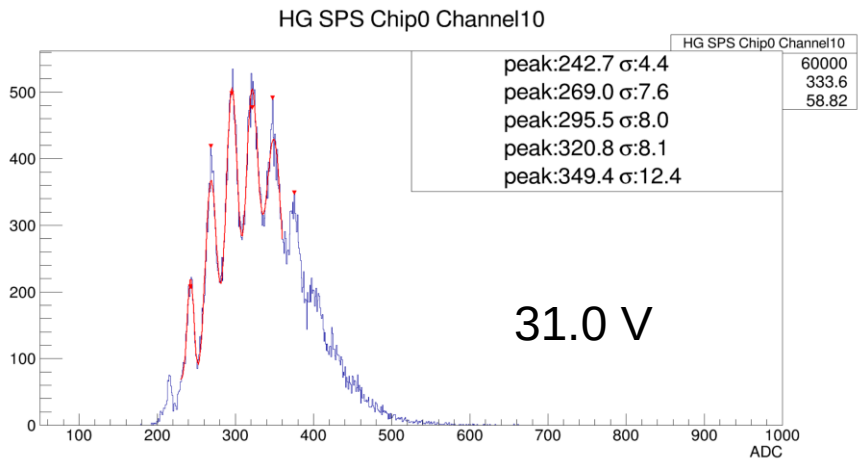
NDL SiPM

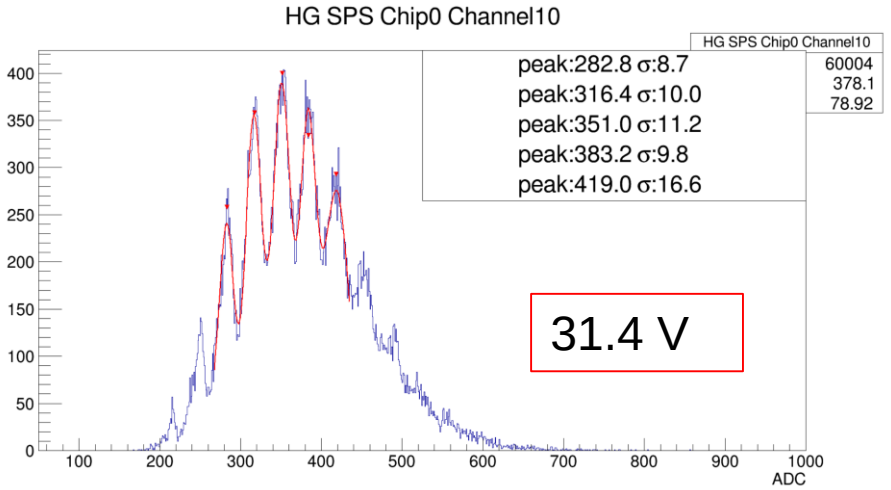
NDL SiPM

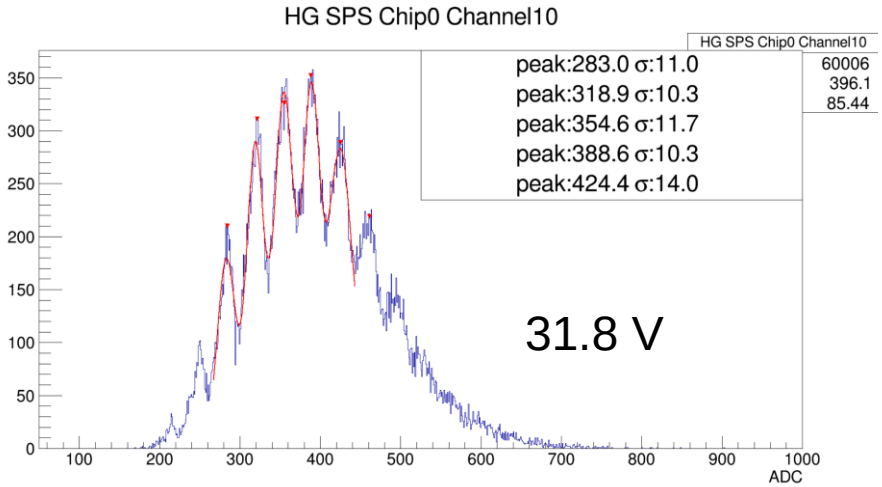


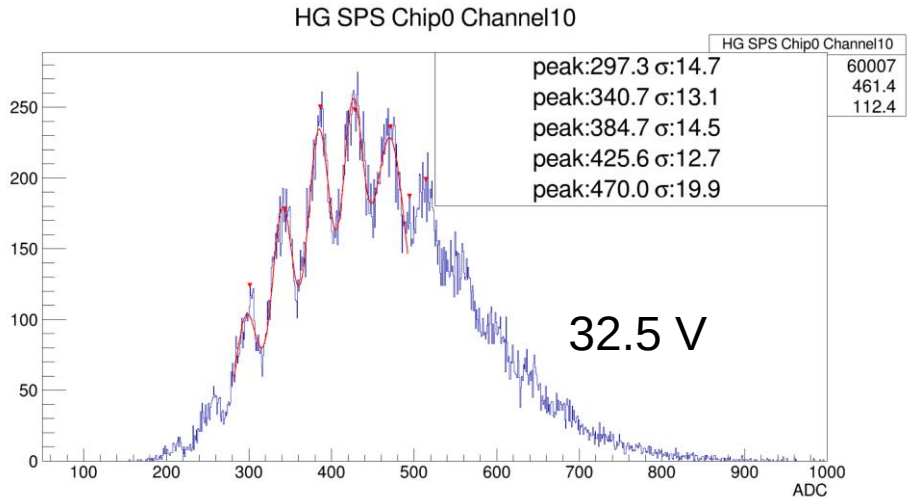
I-V curve

NDL SiPM photon electron spectrum



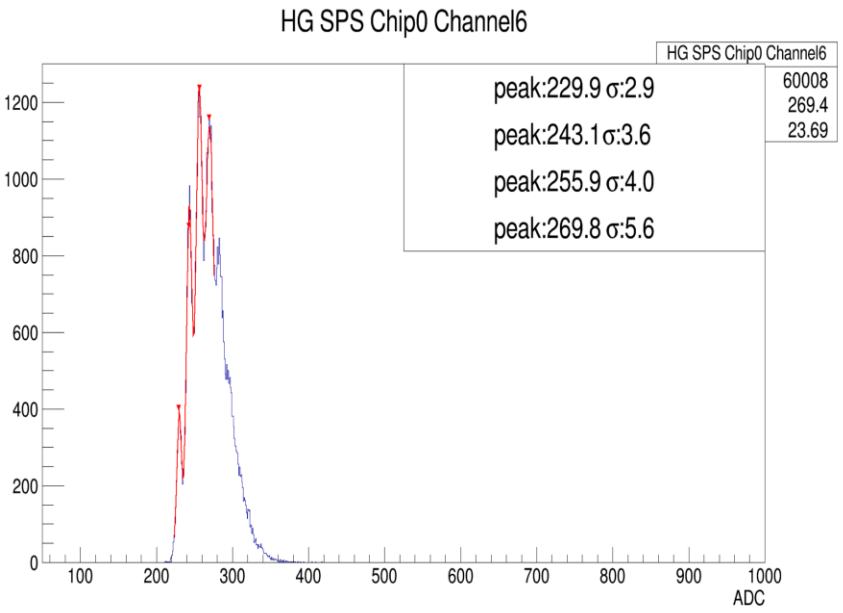


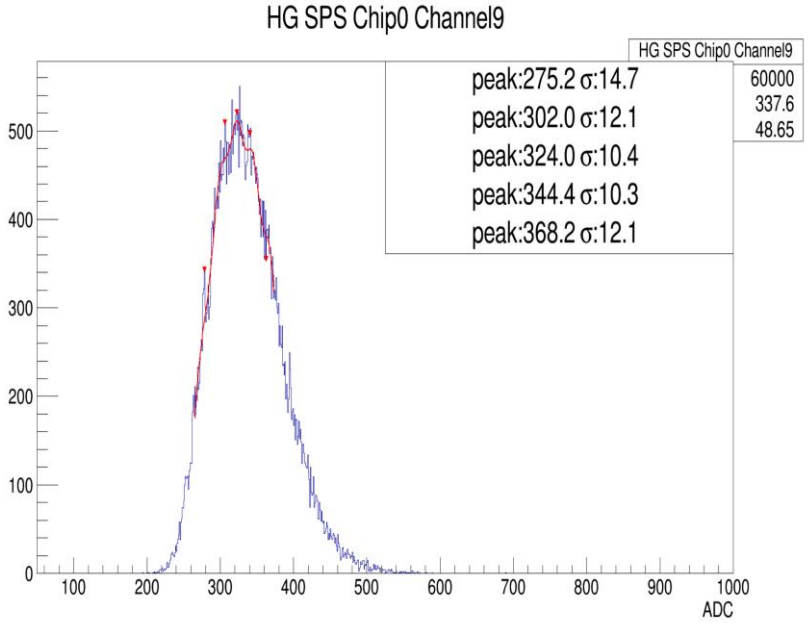




NDL SiPM photon electron spectrum

- we found that the SNR of a few SiPM was very small
- the photoelectric peaks disappeared with the increase of voltage

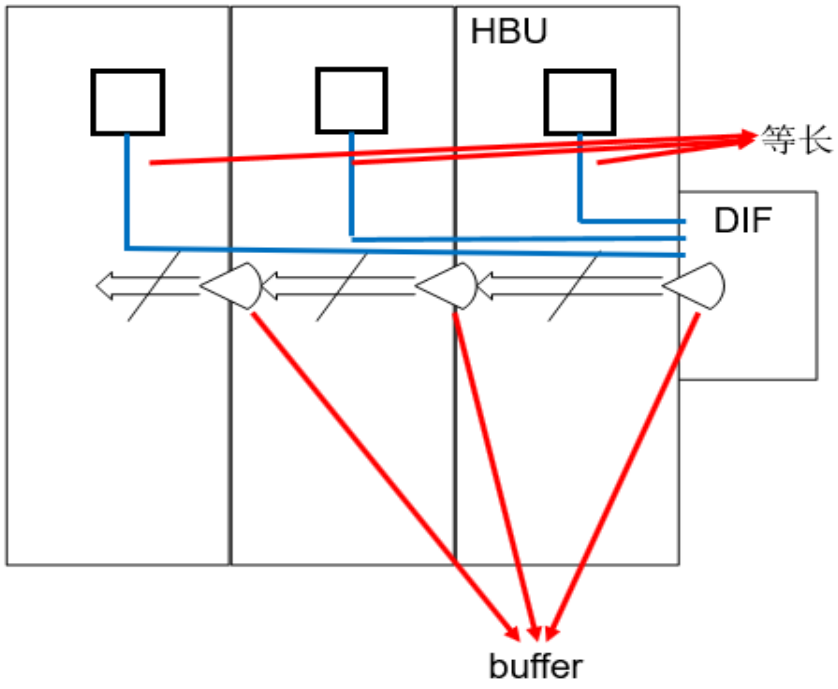




At present, these SiPMs account for 7% of the total

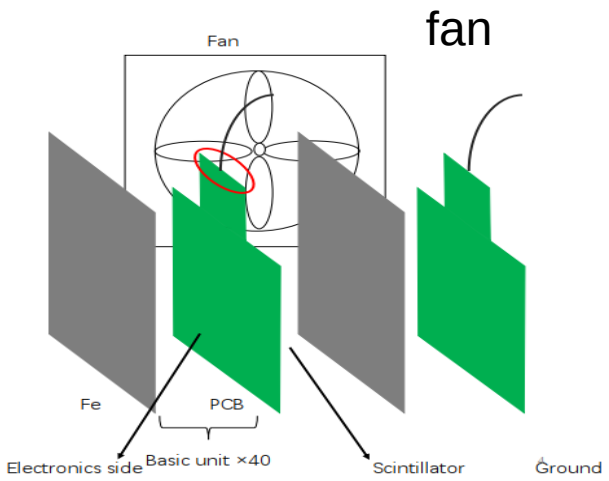
HBU update

- add additional buffer to the sub-board to ensure the signal integrity
- keep real-time control signal among SP2e equaling to ensure all the SP2e in a same condition



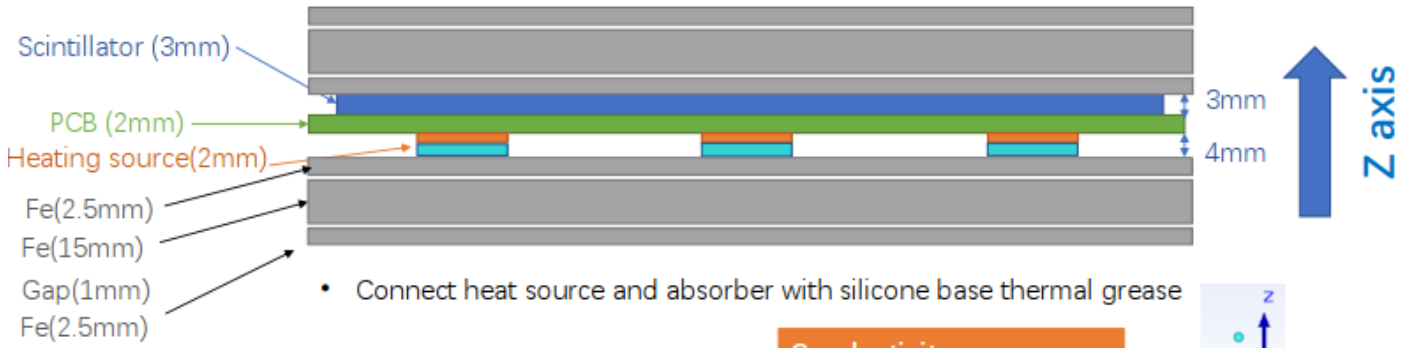
Cooling simulation

- The power consumption of each layer of HBU is about 4 W
- The main heat sources are electronic chips
- In order to reduce the influence of temperature, we add some fans next to the AHCAL



Fe-Heating source-PCB-Scintillator-Fe

(Fe-Heating source-PCB-Scintillator)*n-Fe



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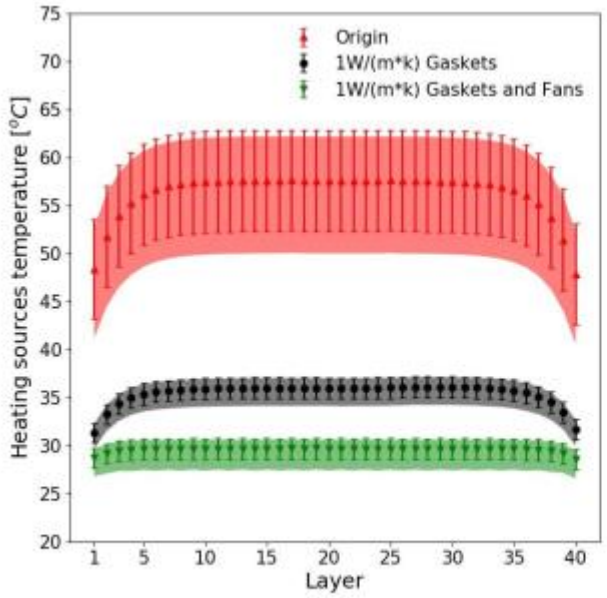
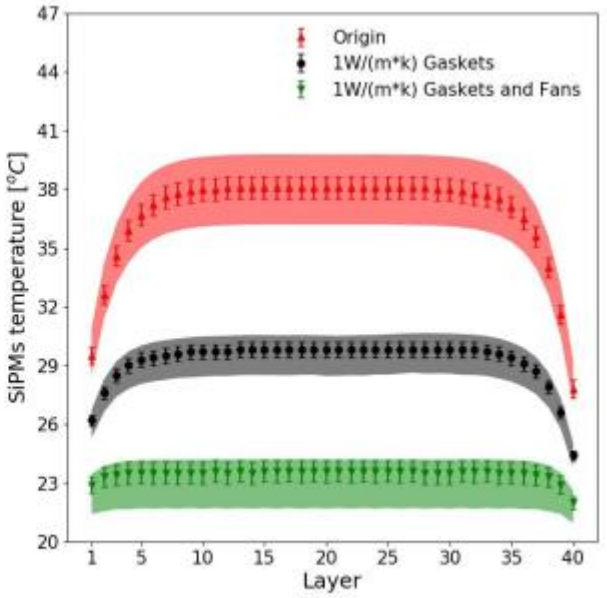


Heating sources

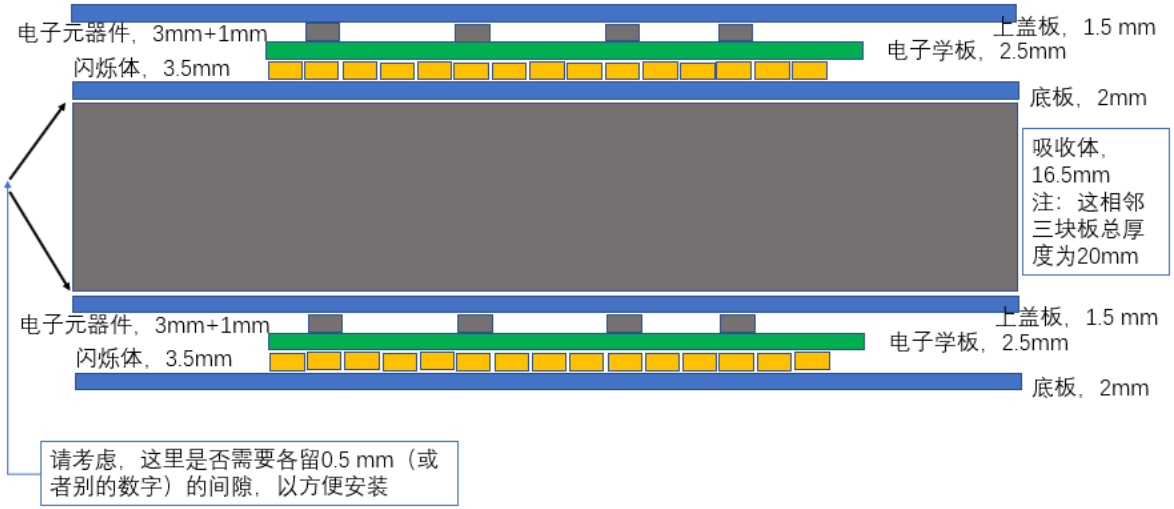


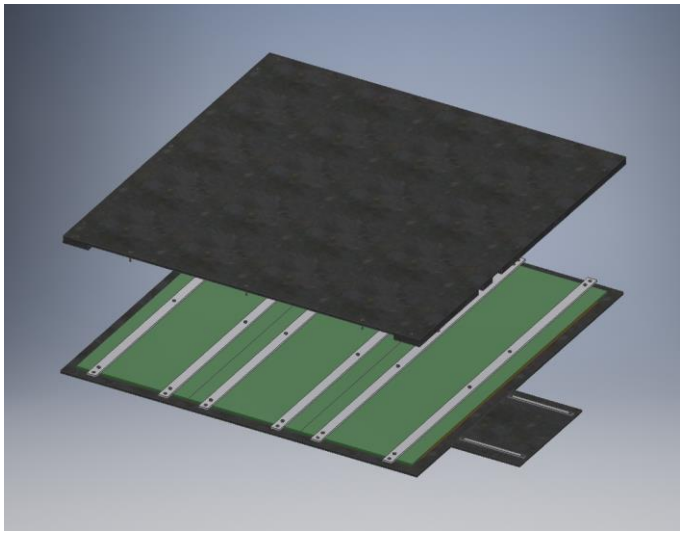
SiPMs

- For heating sources: The mean temperature of the origin: 48℃ to 58℃. Thermal conductive rubbers reduce the mean temperature by about 20℃. Fans further reduce the average temperature by about 6℃.
- For SiPMs: The mean temperature of the origin: 28℃ to 38℃. Thermal conductive rubbers reduce the mean temperature by about 8℃. Fans further reduce the average temperature by about 6℃.

HBU box mechanical design

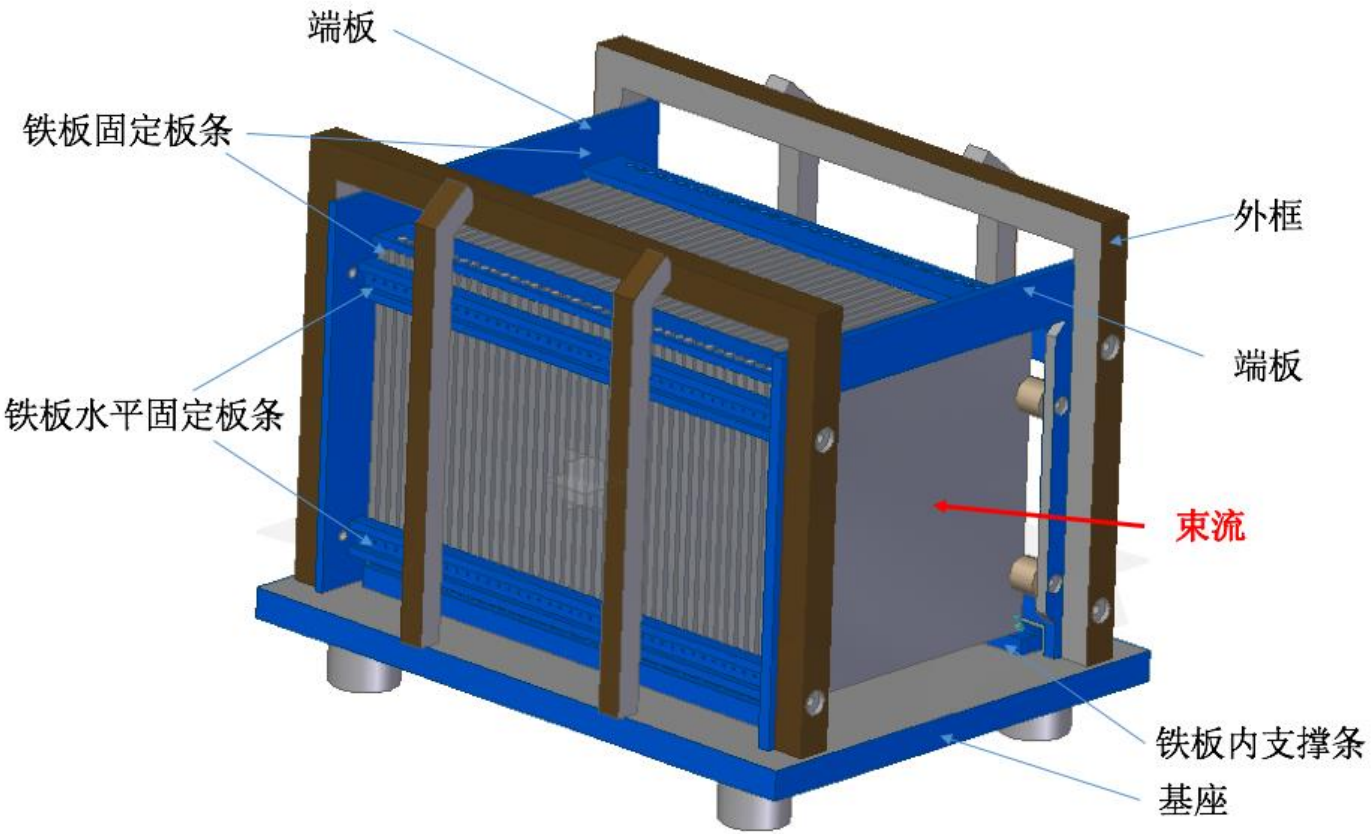
- In order to facilitate testing and transportation, each HBU has a cassette
- We choose iron as the material of the box, and the mass of this part is directly deducted from the absorber





HBU box mechanical design

Then we can install these cassettes directly into the supporting structure of the prototype



Summary and outlook

- The light yield test of all scintillators has been completed.
  - A total of 14219 / 15524 scintillators meet our requirement (the prototype needs 13960)
- Two SiPM test systems are developed and applied to the performance test
  - One is for SiPM of HAMAMATSU, the other is for NDL
- The new HBU has been sent for processing
- Under the existing power consumption, the influence of air cooling design on the temperature of AHCAL was simulated
  - The design of fan + thermal conductive rubber pad can effectively reduce the temperature of the AHCAL
- HBU cassette processing is being carried out
- We hope to have some results about the new HBU next meeting

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THANKS

backup

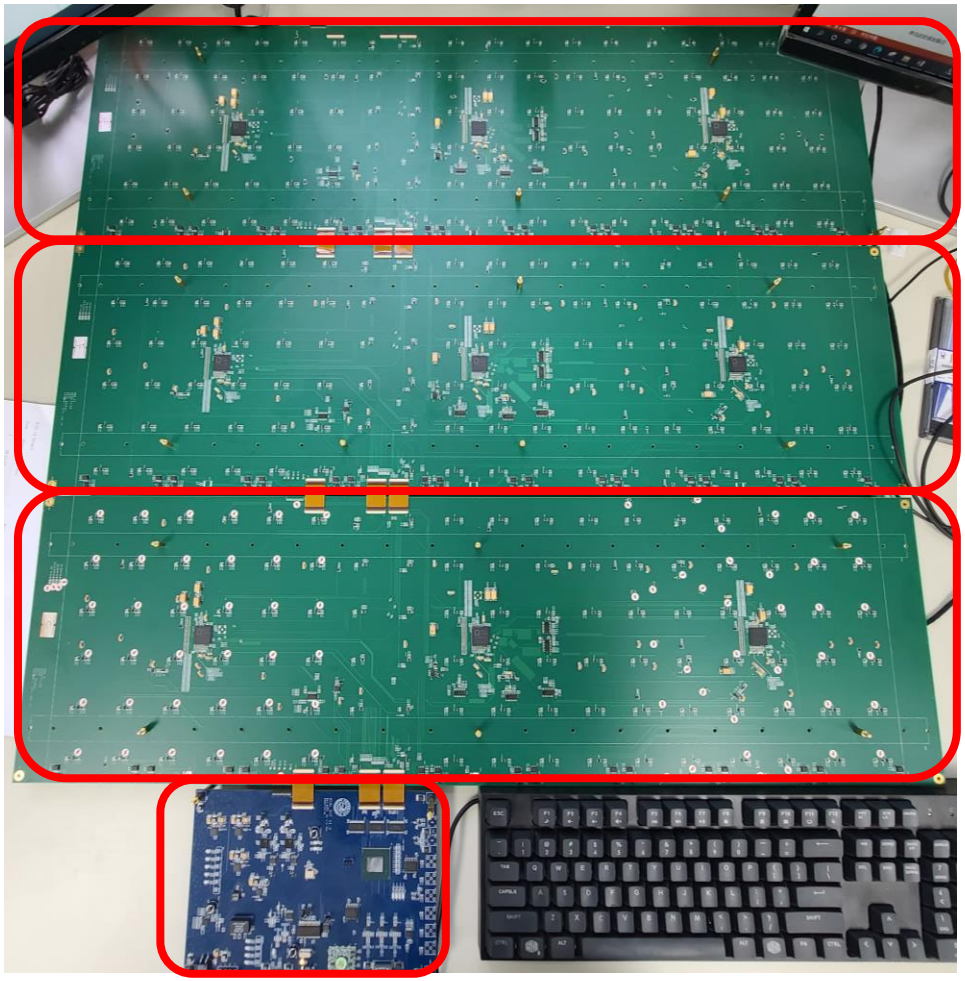
HCAL Baseboard Unit Status

- One layer has 3 sub-HBUs
- One sub-HBU is $78.5 \times 24 \mathrm{cm}^2$
- Flexible boards are used to transmit power and signal between the 3 sub-HBUs and DIF
- Each sub-HBU has 3 SPIROC2E chips
  - The chips were packaged in China

ECAL

AHCAL

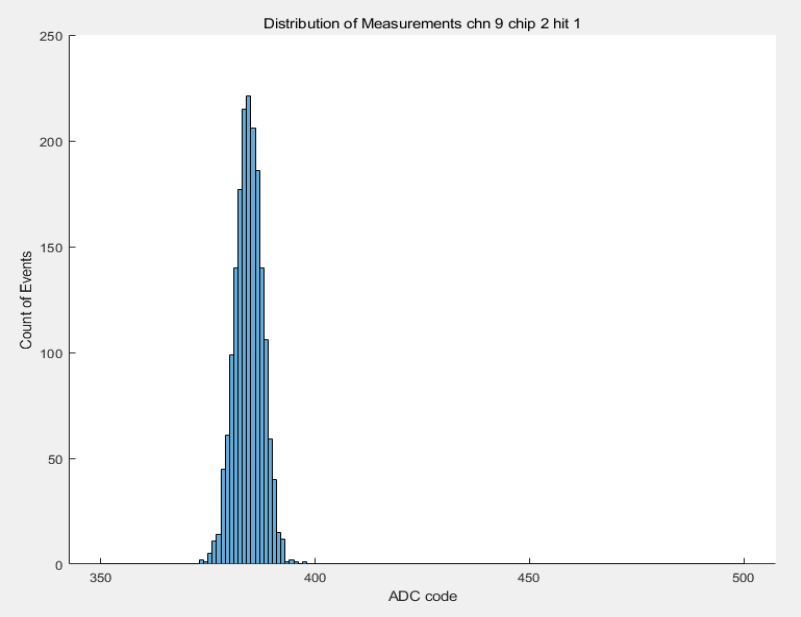
HBU



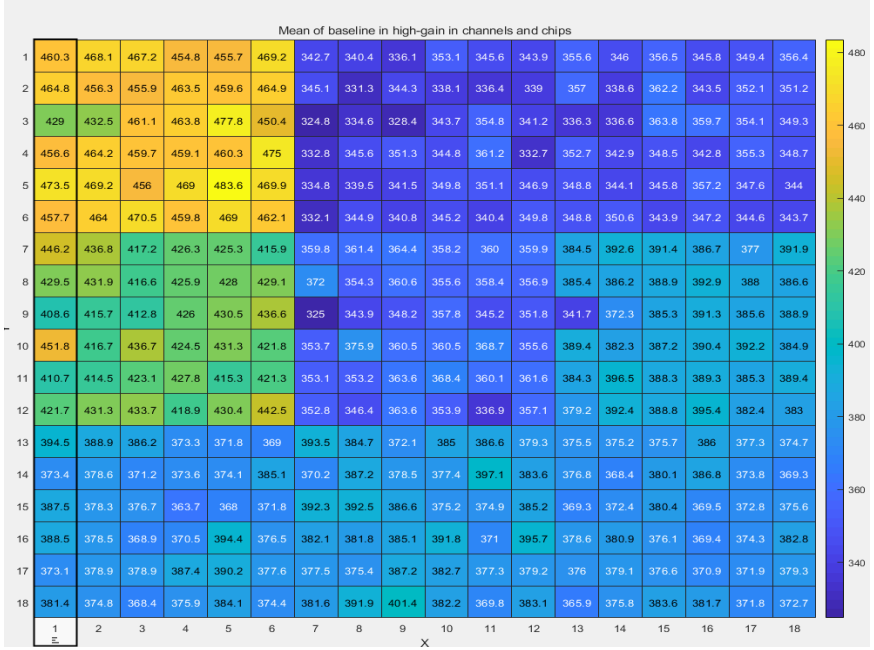
Data InterFace （DIF） board

Pedestal of HBU

- The pedestal of each channel was calibrated using random trigger
- The pedestal positions are differences between chips
- The channels of the same chip are relatively uniform
- The pedestal width has little to do with the chip



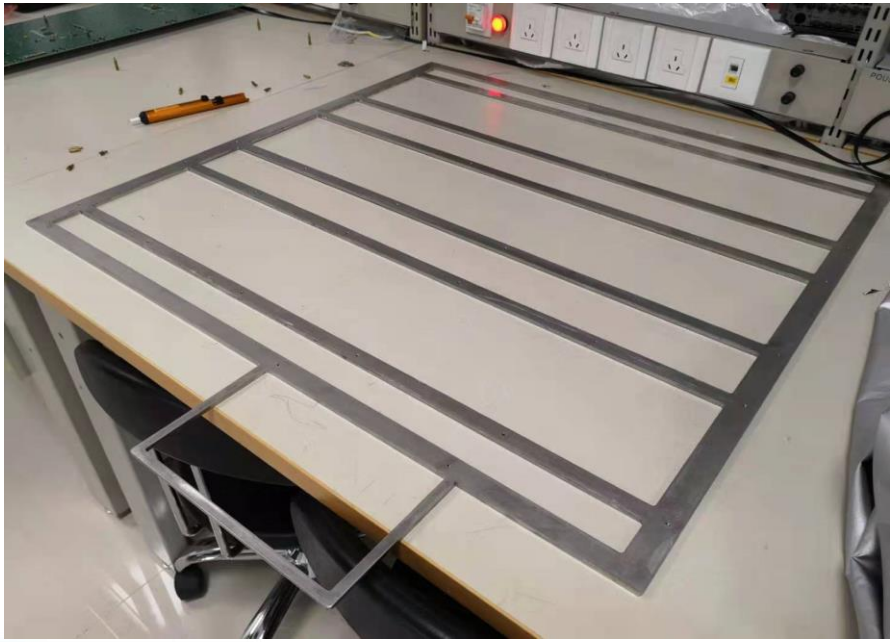
The pedestal of one channel



The pedestal of each channel in HBU

HBU Support Frame

- A 5mm thick Al support frame is machined for trial assembly and testing with HBU
- The optimization of the support frame will be discussed next step



HBU temperature Monitor